



**Smart Cards;
UICC-Terminal interface;
Physical, electrical and logical test specification;
Part 1: Terminal features
(Release 14)**

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ETSI

650 Route des Lucioles
F-06921 Sophia Antipolis Cedex - FRANCE

Tel.: +33 4 92 94 42 00 Fax: +33 4 93 65 47 16

Siret N° 348 623 562 00017 - NAF 742 C
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Full standard available at
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The present document is part 1 of a multi-part deliverable covering the UICC-Terminal interface; Physical, electrical and logical test specification, as identified below:

Part 1: "Terminal features";

Part 2: "UICC features".

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Introduction

The present document defines the interface tests for the Terminal/UICC interface.

The aim of the present document is to ensure interoperability between an UICC and a Terminal independently of the respective manufacturer, card issuer or operator.

Application specific tests for applications residing on an UICC are specified in ETSI TS 131 121 [4].

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